

Notice of References Cited	Application/Control No. 10/822,960	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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*	C	US-6,410,927	06-2002	Pike, Christopher Lee	250/491.1
*	D	US-6,512,227	01-2003	Iwabuchi et al.	250/310
*	E	US-6,841,008	01-2005	Branco et al.	134/26
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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